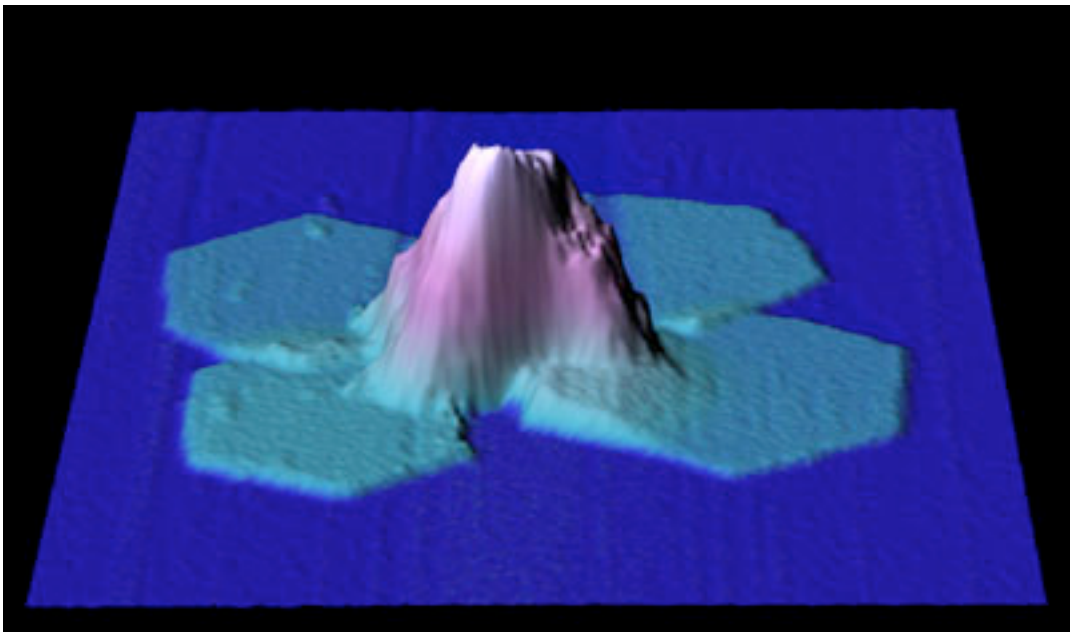
Sample images – Lloyd Whitman



Lead Disulfide Patterned by DPN - Atomic force microscopy (AFM) image of lead disulfide microcrystals grown on a silicon oxide surface patterned by the AFM using "Dip-pen Nanolithography" (DPN).

Sunrise over Si(114) - An artistic view of the atomic-scale topography of Si(114) as revealed by scanning tunneling microscopy. The tallest rows of atoms are 1.63 nm apart, with the atoms visible along these rows separated by 0.77 nm.